



FORM PTO-1449 (Modified)

LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION DISCLOSURE
STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.
KLR 1016.2085

SERIAL NO.
10/672,655

APPLICANT
Dunklee, et. al.

FILING DATE
Sept. 25, 2003

GROUP

2829, Emily Chan

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
EC	AA	4,906,920	Mar. 6, 1990	Huff, et. al.	—	—	
EC	AB	5,266,889	Nov. 30, 1993	Harwood, et. al.	—	—	
EC	AC	5,434,512	July 18, 1995	Schwindt, et. al.	—	—	
EC	AD	5,457,398	Oct. 10, 1995	Schwindt, et. al.	—	—	
EC	AE	5,530,371	June 25, 1996	Perry, et. al.	—	—	
EC	AF	5,546,012	Aug. 13, 1996	Perry, et. al.	—	—	
EC	AG	5,610,529	Mar. 11, 1997	Schwindt	—	—	
EC	AH	5,629,631	May 13, 1997	Perry, et. al.	—	—	
EC	AI	5,835,997	Nov. 10, 1998	Yassine	—	—	
EC	AJ	5,963,027	Oct. 5, 1999	Peters	—	—	
EC	AK	6,002,263	Dec. 14, 1999	Peters, et. al.	—	—	
EC	AL	6,031,383	Feb. 29, 2000	Streib, et. al.	—	—	
EC	AM	6,060,891	May 9, 2000	Hembree, et. al.	—	—	
EC	AN	6,121,783	Sept. 19, 2000	Homer, et. al.	—	—	
EC	AO	6,124,723	Sept. 26, 2000	Costello	—	—	
EC	AP						
EC	AQ						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
EC	BA	JP11031724	Feb. 2, 1999	Japan	—	—		
	BB							



OTHER ART

EC	CA	Knauer, William, "Fixtures for Low-Current/Low-Voltage Parametric Testing," <i>Evaluation Engineering</i> , pp. 150-153, November 1990.
	CB	
	CC	
	CD	

Examiner Signature	<i>Emily Chan</i>	Date Considered	<i>8-7-05</i>
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Unique citation designation number. * Applicant is to place a check mark here if English language translation is attached.

Q:\Bonnie Dillon\KLR\CASCADE MICROTECH\Form 1449 file 1016.0085.wpd;
November 21, 2003 (6:25PM)